

Special Issue on Deep Learning for Document Analysis and Recognition

International Journal on Document Analysis and Recognition

Deep learning is a new field of machine learning research, to design models and learning algorithms for deep neural networks. Due to the ability of learning from big data and the superior representation and prediction performance, deep learning has gained great successes in various applications of pattern recognition and artificial intelligence, including character and text recognition, image segmentation, object detection and recognition, face recognition, traffic sign recognition, speech recognition, machine translation, to name a few. Intensive attention has been drawn to the exploration of new deep learning models and algorithms, and the extension to more application areas. The combination of deep learning and traditional methods in pattern recognition and artificial intelligence has also demonstrated benefits.

The technology of document analysis and recognition (DAR) is to analyze the structure and textual contents of document images and handwriting. It faces numerous application needs such as digitization of books and forms, pen-based text input, information extraction from Web document images. It has been under study as a field of pattern recognition since 1960s. In recent years, the introduction of deep learning to DAR has led to significant improvement of performance in many branches, particularly in the cases when large sets of labeled data are available for supervised learning, such as handwritten character and text recognition. Among the most successful deep learning models are the convolutional neural network (CNN) and the recurrent neural network with long short-term memory (LSTM). The application of deep learning is now extended to scene text detection and recognition, document image segmentation and layout analysis, writer identification, document retrieval, and so on.

This special issue is aimed to report the new advances in DAR using deep learning methods. Articles presenting reviews, perspectives, new methods and applications in DAR are cordially invited. The topics of interest include, but are not limited to

- Deep learning for document image processing and segmentation
- Deep learning for layout analysis
- Deep learning for character and text recognition
- Deep learning for scene text detection and recognition
- Deep learning for writer identification and signature analysis
- Deep learning for document retrieval
- Deep learning for context modeling
- Deep learning for graphics and symbol recognition
- Deep learning for other DAR tasks

Schedule

Paper Submission due: August 31, 2017
First review notification: November 30, 2017
Revision submission: January 31, 2018
Acceptance notification: March 31, 2018
Final submission: April 30, 2018

Guest Editors

Cheng-Lin Liu, Institute of Automation of Chinese Academy of Sciences, China

Email: liucl@nlpr.ia.ac.cn

Gernot A. Fink, TU Dortmund University, Germany

Email: Gernot.Fink@tu-dortmund.de

Venu Govindaraju, University at Buffalo, USA

Email: govind@buffalo.edu

Lianwen Jin, South China University of Technology, China

Email: eelwjin@scut.edu.cn

Bios of guest editors

Cheng-Lin Liu is a Professor at the National Laboratory of Pattern Recognition (NLPR), Institute of Automation of Chinese Academy of Sciences, Beijing, China, and is now the director of the laboratory. He received the B.S. degree in electronic engineering from Wuhan University, Wuhan, China, the M.E. degree in electronic engineering from Beijing Polytechnic University, Beijing, China, the Ph.D. degree in pattern recognition and intelligent control from the Chinese Academy of Sciences, Beijing, China, in 1989, 1992 and 1995, respectively. He was a postdoctoral fellow at Korea Advanced Institute of Science and Technology (KAIST) and later at Tokyo University of Agriculture and Technology from March 1996 to March 1999. From 1999 to 2004, he was a research staff member and later a senior researcher at the Central Research Laboratory, Hitachi, Ltd., Tokyo, Japan. His research interests include pattern recognition, image processing, neural networks, machine learning, and especially the applications to character recognition and document analysis. He has published over 200 technical papers at prestigious international journals and conferences. He won the IAPR/ICDAR Young Investigator Award of 2005. He is on the editorial board of Pattern Recognition Journal, Image and Vision and Computing, International Journal on Document Analysis and Recognition, and Cognitive Computation. He is a Fellow of the IAPR and the IEEE.

Gernot A. Fink received the diploma in computer science from the University of Erlangen-Nuremberg, Erlangen, Germany, in 1991 and the Ph.D. degree (Dr.-Ing.) also in computer science from Bielefeld University, Germany, in 1995. In 2002 he received the *venia legendi* (Habilitation) in Applied Computer Science from Bielefeld

University. From 1991 to 2005 he was with the Applied Computer Science Group at the Faculty of Technology of Bielefeld University. Since 2005 he is professor for Pattern Recognition in Embedded Systems within the Department of Computer Science at TU Dortmund University, Dortmund, Germany. His research interests lie in fields of statistical pattern recognition, machine perception including machine hearing and computer vision, and document image analysis with a focus on handwriting recognition. Dr. Fink has published more than 180 papers in these fields and is the author of a textbook on Markov-model based techniques for pattern recognition problems. His recent work on Deep Learning for wordspotting won both a competition track and the Best Paper Award at ICFHR 2016. Dr. Fink currently serves as Associate Editor for the International Journal of Pattern Recognition and Artificial Intelligence (IJPRAI) and for the International Journal of Document Analysis and Recognition (IJ DAR). He is Senior Member of the Institute of Electrical and Electronics Engineers (IEEE), the IEEE Signal Processing Society, and the IEEE Computer Society.

Venu Govindaraju, SUNY Distinguished Professor of Computer Science and Engineering with the University at Buffalo. He is the founding director of the Center for Unified Biometrics and Sensors. He has co-authored about 400 refereed scientific papers and has supervised the dissertations of 36 doctoral students. He has served on the editorial boards of premier journals such as the IEEE Transactions on Pattern Analysis and Machine Intelligence and IEEE Transactions on Information Forensics and Security. Govindaraju is a Fellow of the ACM (Association for Computing Machinery), the IEEE (Institute of Electrical and Electronics Engineers), the AAAS (American Association for the Advancement of Science), the IAPR (International Association of Pattern Recognition), and the SPIE (International Society of Optics and Photonics). He is the recipient of the 2001 International Conference on Document Analysis and Recognition Young Investigator award, the 2004 MIT Global Indus Technovator Award, the 2010 IEEE Technical Achievement Award, and the Indian Institute of Technology (IIT) Distinguished Alumnus Award (2014). Dr. Govindaraju is the 2015 IAPR/ICDAR Outstanding Achievements Award Winner and was named a Fellow of the National Academy of Inventors in 2015

Lianwen Jin is a professor in the School of Electronic and Information Engineering, at the South China University of Technology. He received the B.S. degree from the University of Science and Technology of China, Anhui, China, and the Ph.D. degree from the South China University of Technology, Guangzhou, China, in 1991 and 1996, respectively. He is the author of more than 150 scientific papers. Dr. Jin was a recipient of the award of New Century Excellent Talent Program of MOE in 2006 and the Guangdong Pearl River Distinguished Professor Award in 2011. His research interests include handwriting analysis and recognition, image processing, pattern recognition and machine learning, deep learning and intelligent systems.

International Journal on Document Analysis and
Recognition (IJ DAR)

Editors-in-Chief: Kise, K.; Lopresti, D.; Marinai, S.

ISSN: 1433-2833 (print version)

ISSN: 1433-2825 (electronic version)

Journal no. 10032